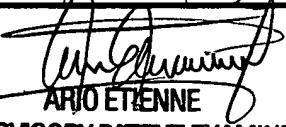
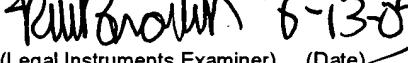
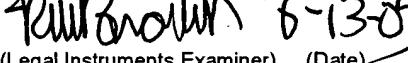
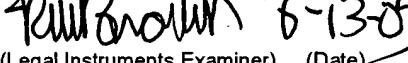
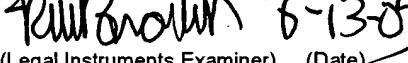
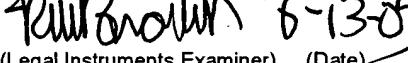
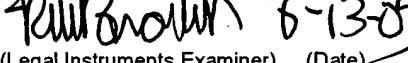
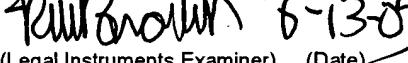
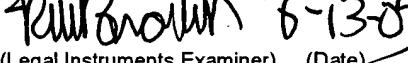
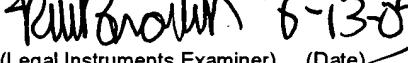
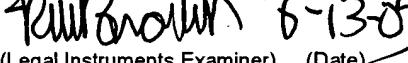
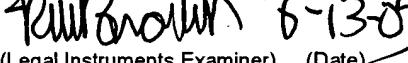
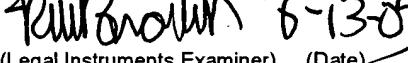
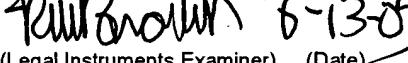
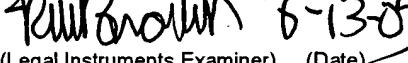
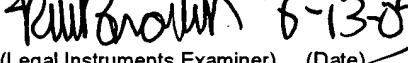
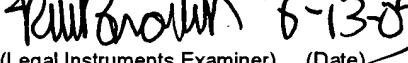
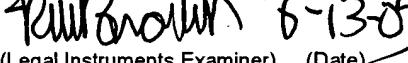
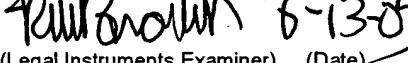
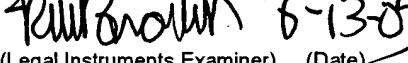
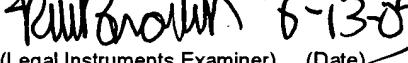
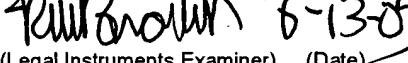
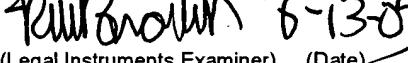
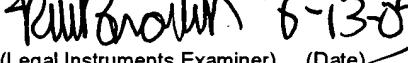
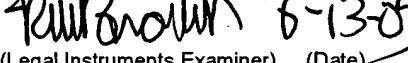
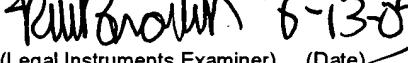
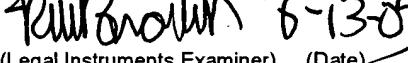
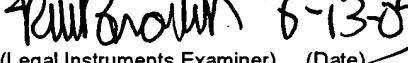
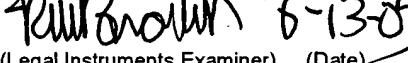
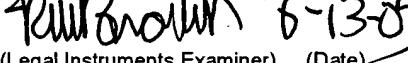
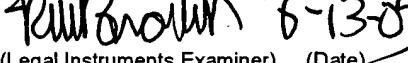
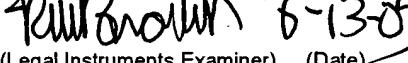
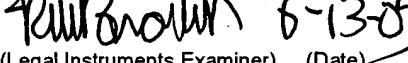
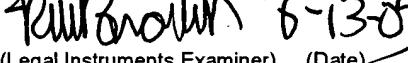
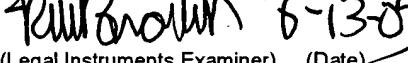
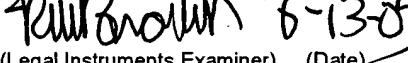
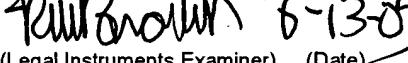
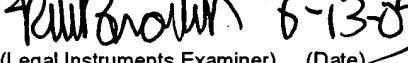
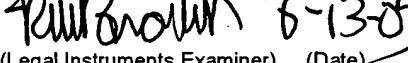
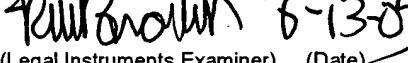
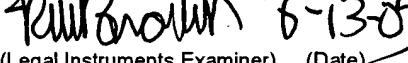
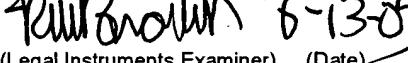
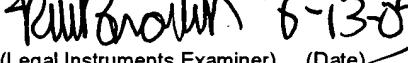
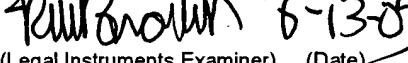
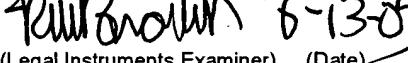
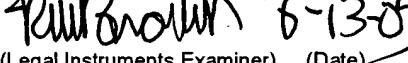
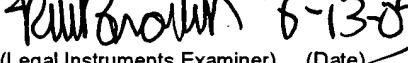
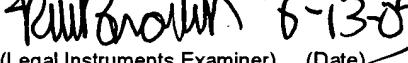
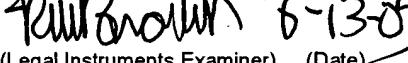
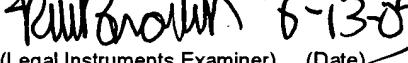
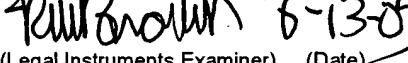
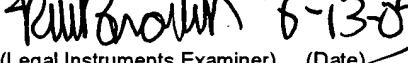
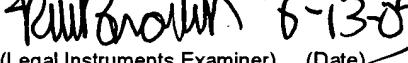
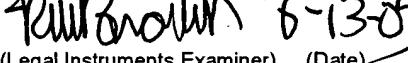
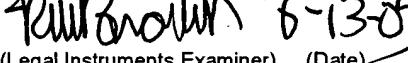
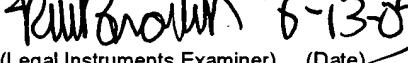
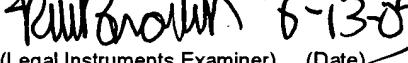
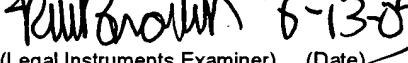
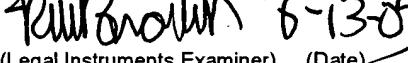
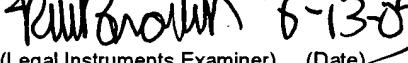
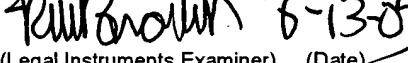
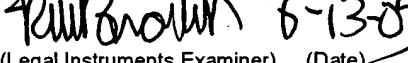
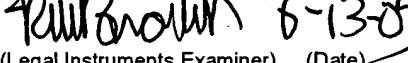
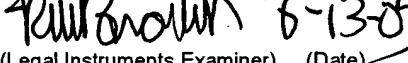
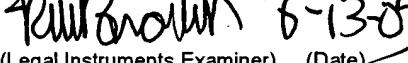
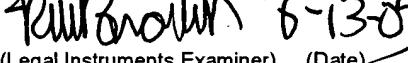
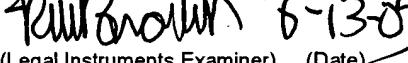
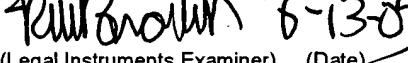
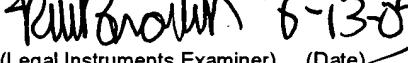
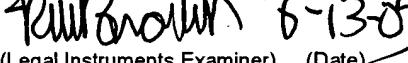
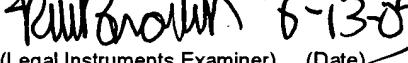
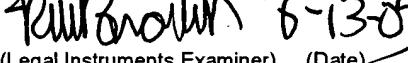
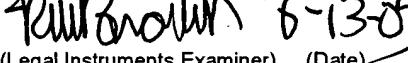
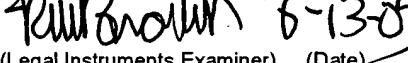
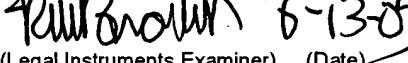
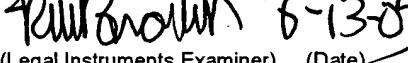
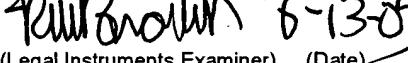
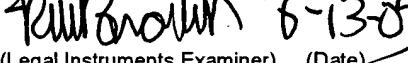
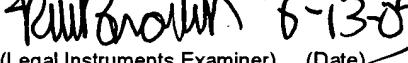
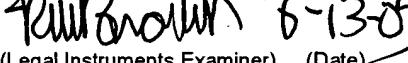
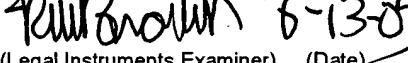
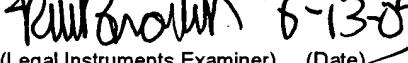
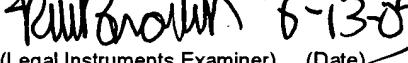
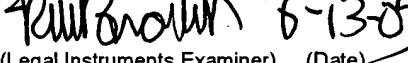
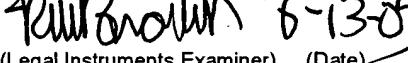
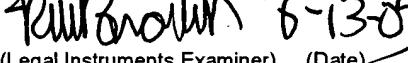
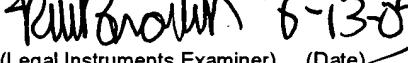
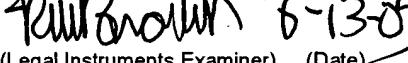
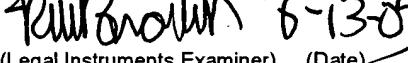
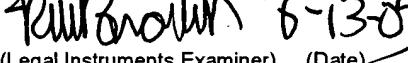
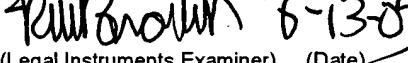
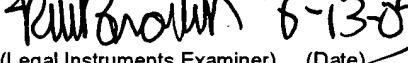
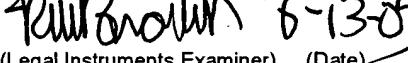
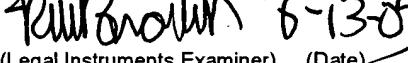
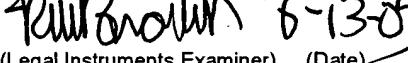
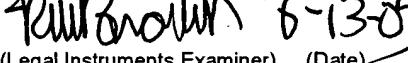
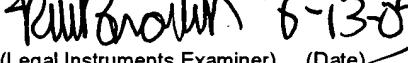
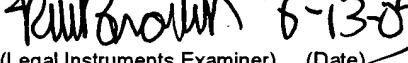
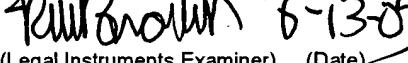
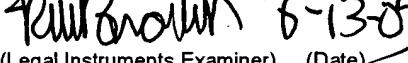
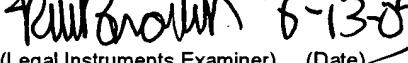
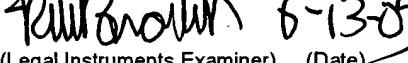
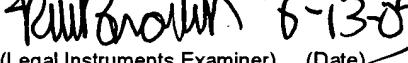
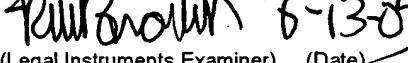
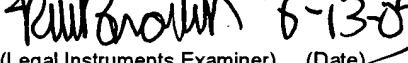
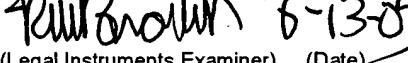
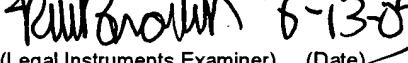


Issue Classification			Application/Control No.	Applicant(s)/Patent under Reexamination	
			09/819,592	LARKY ET AL.	
			Examiner	Art Unit	
			Ramy M. Osman	2157	

ORIGINAL			CROSS REFERENCE(S)					
CLASS	SUBCLASS	CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)					
709	206	709	201	203	206			
INTERNATIONAL CLASSIFICATION			707	6				
60	6F	15 / 16						
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			6/10/05				ARIO ETIENNE	
			6-13-05				Primary Examiner	
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